

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)

YOU-13002/00

Application Number

10/523,874

Applicant(s)

Jong-In Lee et al.

Filing Date

February 7, 2005

Group Art Unit

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE



U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
<i>JP</i>		07-053457	02/28/1995	Japan			✓	

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

J. Dan

DATE CONSIDERED

1/16/06

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YOU-13002/09

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JP		5,183,933	2/2/1993	Harper et al.			
JP		4,950,786	8/21/1990	Sanchez et al.			

U.S. PATENT APPLICATION PUBLICATIONS

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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
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JP		WO 1999/018059	4/15/1999	WIPO				
JP		WO 2003/022791	3/20/2003	WIPO				
JP		JP 06 279356 A2	10/4/1994	JAPAN			✓	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

J. Dowd

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